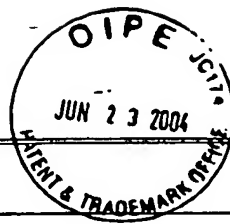


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 238397US-2 DIV		APPLN. SERIAL NO. NEW APPLICATION 62/657,121			
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT NATSUKO NOBUKUNI, ET AL.		FILED HEREWITH		GROUP 2655	
U.S. PATENT DOCUMENTS									
EXAMINER INITIAL	CLASS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE		
12/9	AA	5,732,062	03/24/98	Yokoi, et al.					
12/9	AB	5,848,043	12/08/98	Takada, et al.					
12/9	AC	5,530,688	06/1996	Hurst, Jr., et al.					
12/9	AD	6,294,310	09/2001	Ohno, et al.					
12/9	AE	5,703,855	12/1997	Kirino et al.					
12/9	AF	5,568,461	10/1996	Nishiuchi, et al.					
12/9	AG	6,256,277 B1	07/03/01	Saga et al.					
	AH								
	AI								
	AJ								
	AK								
	AL								
	AM								
	AN								
FOREIGN PATENT DOCUMENTS									
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION				
					YES	NO			
12/9	AO	62-259229	11/11/87	Japan			x		
12/9	AP	63-266632	11/02/88	Japan			x		
12/9	AQ	63-22439	01/29/88	Japan			x		
12/9	AR	7-37252	02/07/95	Japan			x		
12/9	AS	9-7176	01/10/97	Japan			x		
12/9	AT	8-287465	11/01/96	Japan			x		
12/9	AU	9-282661	10/31/97	Japan			x		
12/9	AV	7-37251	02/07/95	Japan			x		
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)									
12/9	AW	N. Nobukuni, et al. J. Appl Physics, "Microstructural changes in GeSbTe film during repetitious overwriting in phase-change optical recording," December 15, 1995, pages 6980-6988.							
	AX								
	AY								
	AZ								
Examiner		Muhammad Edun Primary Examiner			Date Considered		10/12/04		

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 238397US-2 DIV		APPLN. SERIAL NO. NEW APPLICATION 10/677,121	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT NATSUKO NOBUKUNI, ET AL.			
				FILED HEREWITH		GROUP 2655	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	0 887 888	09/30/98	Europe (English)			
	AP	0 902 424	03/17/99	Europe (English)			
	AQ	0 388 897	09/26/90	Europe (English)			
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						
Examiner		Muhammad Edun Primary Examiner			Date Considered 10/17/04		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 238397US2DIV		SERIAL NO. 10/657,121	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Natsuko NOBUKUNI, et al.			
				FILING DATE September 9, 2003		GROUP 2655	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>HE</i>	AA	6,256,286	07/03/2001	M. OGAWA			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>HE</i>	AO	0 847 049	06/10/1998	EUROPE			
<i>HE</i>	AP	0 217 293	04/08/1987	EUROPE			
<i>HE</i>	AQ	0 834 874	04/08/1998	EUROPE			
<i>HE</i>	AR	1 047 058	10/25/2000	EUROPE			
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>HE</i>	AW	M. HORIE, et al., Optical Data Storage, Proceedings of SPIE, vol. 4342, XP-002267102, pages 76-87. "MATERIAL CHARACTERIZATION AND APPLICATION OF EUTECTIC SbTe BASED PHASE-CHANGE OPTICAL RECORDING MEDIA", April, 2001					
<i>HE</i>	AX	Patent Abstracts of Japan, JP 10-241160, September 11, 1998					
<i>HE</i>	AY	Patent Abstracts of Japan, JP 61-020236, January 29, 1986					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner		Muhammad Edun Primary Examiner			Date Considered <i>10/17/04</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



LIST OF RELATED CASES

<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Inventor/ Applicant</u>
238397US2 DIV*	10/657,121	09/09/03	NOBUKUNI et al.
250703US2 RE	10/825,439	04/16/04	NOBUKUNI et al.

Muhammad Edun
Primary Examiner

10/17/04

*Present Application; listed for information

GJM/sba

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